

UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner: To Be Assigned	Art Unit: To Be Assigned
Re: Application of:	Ulrich KACZYNSKI
Serial No.:	To Be Assigned
Filed:	Herewith
For:	COORDINATE MEASURING STAGE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

August 1, 2003

S i r:

In accordance with the provisions of 37 C.F.R. § 1.97, Applicant hereby makes of record the documents listed on the accompanying PTO-1449 Form (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. While the references are being submitted herewith, some or all of the references may not constitute prior art under the U.S. patent laws.

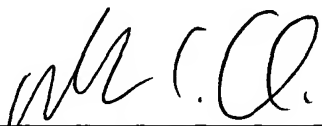
This Information Disclosure Statement is filed under 37 C.F.R. §1.97 (b), before the mailing date of a First Office Action, therefore no fee is believed due.

In the event any additional fee is due in connection with this response or if any fee has been overpaid, the deficiency or overpayment should be charged to our Deposit Account No. 50-0552.

It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully submitted,

DAVIDSON, DAVIDSON & KAPPEL, LLC

By: 
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FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.: 5005.1057

SERIAL NO.: To Be Assigned

LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT(S): Ulrich KACZYNSKI

FILING DATE: Herewith

GROUP: To Be Assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBC LASS	FILING DATE IF APPROPRIATE
	AA	20	03	00	53	0	3	7	Mar. 20, 2003	Blaesing-Bangert et al.	355	53	
	AB												
	AC												
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLAS S	TRANSLATION	
													YES	NO
	AL	1	0	1	4	0	1	74	Mar. 13, 2003	Germany			see U.S. '037	
	AM													
	AN													
	AO													
	AP													

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	K.-D. Röth und K. Rinn, "Maskenmetrologie mit der LEICA LMS IPRO für die Halbleiter-Produktion", Leica Mikroskopie und Systeme GmbH, Wetzlar (Translation - see Application Text)											
	AR												
	AS												

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.